

DCR1595SW

Phase Control Thyristor

Replaces July 2001 version, DS4248-6.1

DS4248-7.0 May 2002

FEATURES

- Double Side Cooling
- High Surge Capability

APPLICATIONS

- High Power Drives
- High Voltage Power Supplies
- DC Motor Control
- Welding
- Battery Chargers

VOLTAGE RATINGS

Part and Ordering Number	Repetitive Peak Voltages V _{DRM} and V _{DRM} V	Conditions
DCR1595SW42	4200	$T_{vi} = 0^{\circ} \text{ to } 125^{\circ}\text{C},$
DCR1595SW41	4100	$I_{DRM} = I_{RRM} = 400 \text{mA},$
DCR1595SW40	4000	V_{DRM} , V_{RRM} $t_p = 10 ms$,
DCR1595SW39	3900	V_{DSM} & V_{RSM} =
DCR1595SW38	3800	V _{DRM} & V _{RRM} + 100V
DCR1595SW37	3700	respectively

Lower voltage grades available.

ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

DCR1595SW38

Note: Please use the complete part number when ordering and quote this number in any future correspondance relating to your order.

KEY PARAMETERS

V_{DRM}		4200V
I _{T(AV)}	(max)	3020A
I _{TSM}	(max)	53750A
dV/dt*		1000V/ μ s
dl/dt		400Α/ μ s

^{*} Higher dV/dt selections available

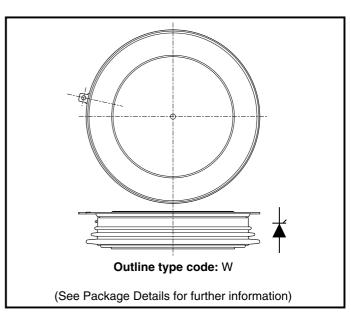


Fig. 1 Package outline



CURRENT RATINGS

 $T_{case} = 60$ °C unless stated otherwise.

Symbol	Parameter	Test Conditions		Units		
Double Side Cooled						
I _{T(AV)}	Mean on-state current	Half wave resistive load	3020	Α		
I _{T(RMS)}	RMS value	-	4745	Α		
I _T	Continuous (direct) on-state current	-	4370	Α		
Single Side Cooled						
I _{T(AV)}	Mean on-state current	Half wave resistive load	1975	Α		
I _{T(RMS)}	RMS value	-	3105	Α		
I _T	Continuous (direct) on-state current	-	2650	Α		

$T_{case} = 80^{\circ}C$ unless stated otherwise.

Symbol	Parameter	Parameter Test Conditions		Units				
Double Sid	Double Side Cooled							
I _{T(AV)}	Mean on-state current	Half wave resistive load	2380	Α				
I _{T(RMS)}	RMS value	-	3735	Α				
I _T	Continuous (direct) on-state current	-	3360	Α				
Single Side	Single Side Cooled							
I _{T(AV)}	Mean on-state current	Half wave resistive load	1530	Α				
I _{T(RMS)}	RMS value	-	2405	Α				
I _T	Continuous (direct) on-state current	-	1996	Α				



SURGE RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
I _{TSM}	Surge (non-repetitive) on-state current	10ms half sine, T _{case} = 125°C	43.0	kA
l²t	I ² t for fusing	$V_{_{\rm R}} = 50\% \ V_{_{\rm RRM}} - 1/4 \ {\rm sine}$	9.25 x 10 ⁶	A²s
I _{TSM}	Surge (non-repetitive) on-state current	10ms half sine, T _{case} = 125°C	53.75	kA
l²t	I ² t for fusing	V _R = 0	14.4 x 10 ⁶	A²s

THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
R _{th(j-c)}	Thermal resistance - junction to case	Double side cooled	DC	-	0.008	°CW
		Single side cooled	Anode DC	-	0.016	°CW
			Cathode DC	-	0.016	°CW
R _{th(c-h)}	Thermal resistance - case to heatsink	Clamping force 70.0kN	Double side	-	0.001	°CW
		(with mounting compound)	Single side	-	0.002	°CW
T _{vj}	Virtual junction temperature	On-state (conducting)		-	135	°C
		Reverse (blocking)		-	125	°C
T _{stg}	Storage temperature range			-55	125	°C
F _m	Clamping force			63.0	77.0	kN



SURGE RATINGS

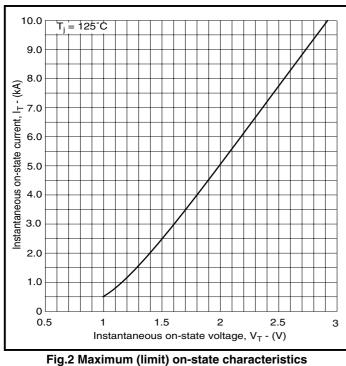
Symbol	Parameter	Test Condition	ons	Min.	Max.	Units
I _{RRM} /I _{RRM}	Peak reverse and off-state current	At V _{RRM} /V _{DRM} , T _{case} = 125°C		-	400	mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V _{DRM} , T _j = 125°C	, gate open	-	1000	V/µs
dl/dt	Rate of rise of on-state current	From 67% V _{DRM} to 2x I _{T(AV)}	Repetitive 50Hz	-	200	A/μs
		Gate source 30V, 10Ω,	Non-repetitive	-	400	A/μs
		t _r < 0.5μs, T _j = 125°C				
V _{T(TO)}	Threshold voltage	At T _{vj} = 125°C		-	1.03	V
r _T	On-state slope resistance	At T _{vj} = 125°C		-	0.19	mΩ
t _{gd}	Delay time	$V_D = 67\% V_{DRM}$, gate source 30V, 15 Ω		0.5	2	μs
		t _r = 0.5μs, Tj = 25°C				
t _q	Turn-off time	$I_{T} = 5000A, t_{p} = 3.5 \text{ms}, T_{j} = 125 ^{\circ}\text{C},$		550	1000	μs
		$V_R = 900V$, $dI_{RR}/dt = 4A/\mu s$,				
		$V_{DR} = 67\% V_{DRM}$				
		dV _{DR} /dt = 20V/μs linear				
IL	Latching current	$T_{j} = 25^{\circ}C, V_{D} = 5V$		220	1000	mA
I _H	Holding current	$T_{j} = 25^{\circ}C, R_{G-K} = \infty, I_{TM} =$	500A, I _T = 5A	50	250	mA



GATE TRIGGER CHARACTERISTICS AND RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
V _{GT}	Gate trigger voltage	V _{DRM} = 5V, T _{case} = 25°C	4	٧
I _{GT}	Gate trigger current	V _{DRM} = 5V, T _{case} = 25°C	400	mA
V _{GD}	Gate non-trigger voltage	At V _{DRM} T _{case} = 125°C	0.25	٧
V _{FGM}	Peak forward gate voltage	Anode positive with respect to cathode	30	٧
V _{FGN}	Peak forward gate voltage	Anode negative with respect to cathode	0.25	٧
V _{RGM}	Peak reverse gate voltage	-	5	V
I _{FGM}	Peak forward gate current	Anode positive with respect to cathode	30	А
P _{GM}	Peak gate power	See table fig. 8 and 9	150	W
P _{G(AV)}	Mean gate power	-	10	W

CURVES



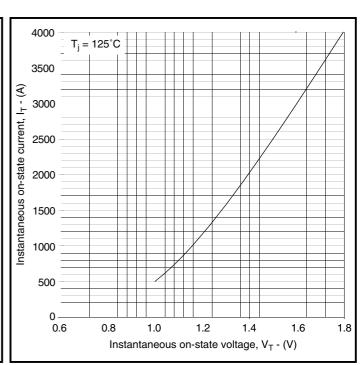


Fig.3 Maximum (limit) on-state characteristics

V_{TM} EQUATION

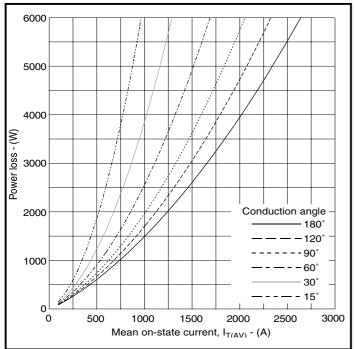
$$V_{TM} = A + Bln (I_T) + C.I_T + D.\sqrt{I_T}$$

A = 0.02866651Where B = 0.1590393 $C = 1.947584x10^{-4}$

 $D = -5.23298x10^{-3}$

these values are valid for $T_j = 125^{\circ}C$ for $I_T 500A$ to 10000A





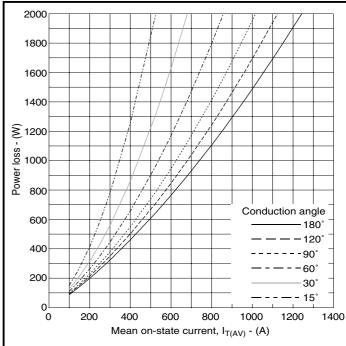
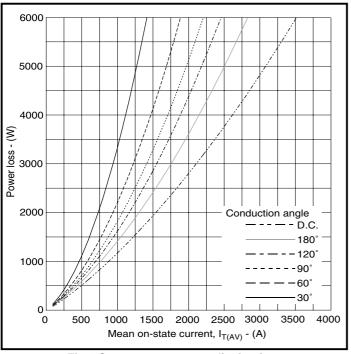
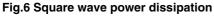


Fig.4 Sine wave power dissipation

Fig.5 Sine wave power dissipation





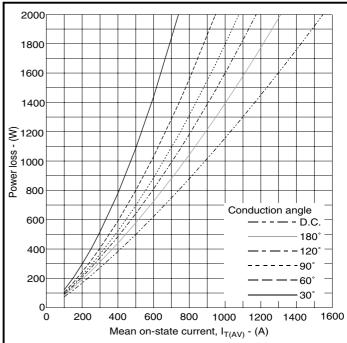


Fig.7 Square wave power dissipation



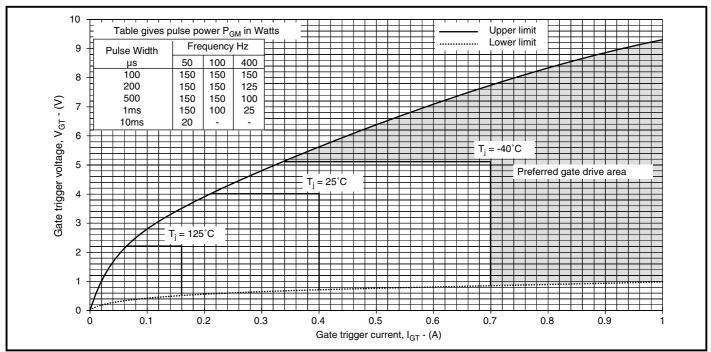


Fig.8 Gate characteristics

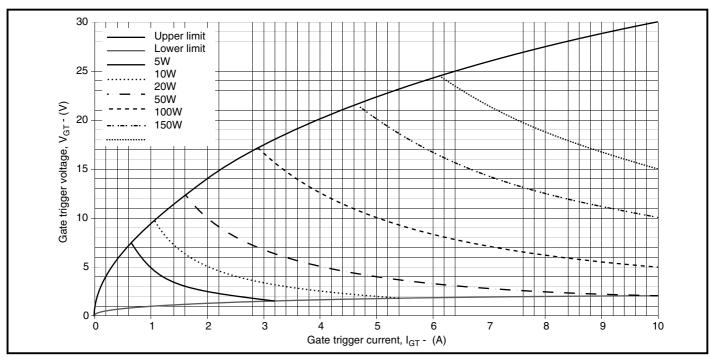


Fig.9 Gate characteristics



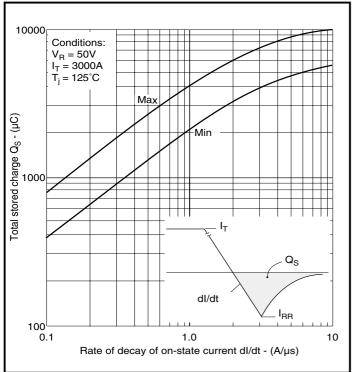


Fig.10 Stored charge

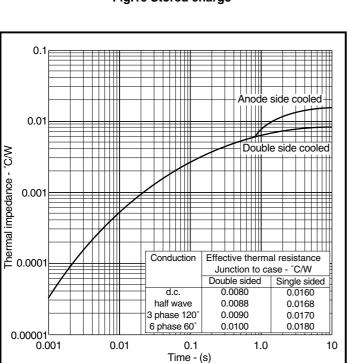


Fig.12 Maximum (limit) transient thermal impedance - junction to case (°C/W)

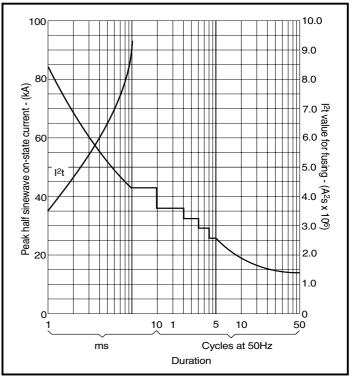
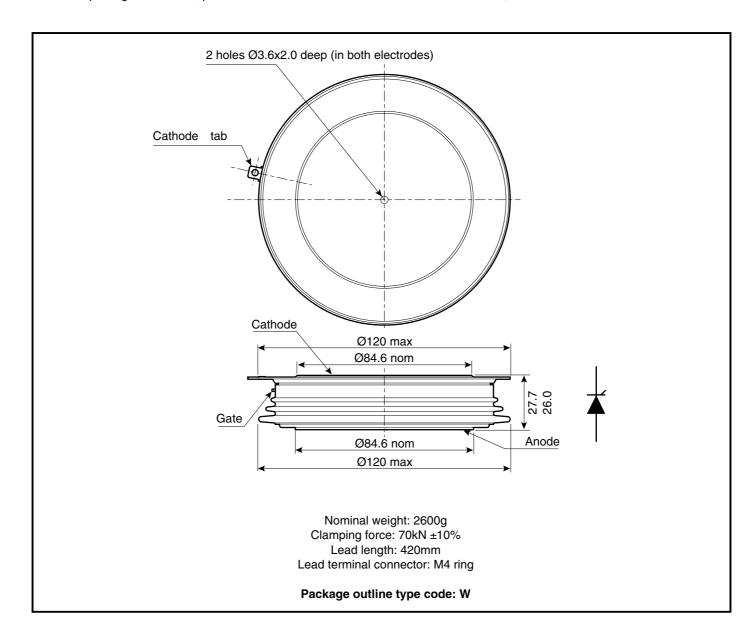


Fig.11 Surge (non-repetitive) on-state current vs time (with 50% V_{RRM} at $T_{case} = 125$ °C)



PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.



POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



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